

Notice of References Cited	Application/Control No. 10/527,514	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0058846	03-2005	Matsui et al.	428/480
*	B	US-5,747,174	05-1998	Kimura et al.	428/480
*	C	US-2005/0100723	05-2005	Tanaka et al.	428/220
*	D	US-3,889,870	06-1975	Bender, Hugo	383/121
*	E	US-4,692,327	09-1987	Takahashi et al.	428/458
*	F	US-4,874,647	10-1989	Yatsu et al.	428/35.7
*	G	US-5,604,019	02-1997	Bland et al.	428/212
*	H	US-6,652,979	11-2003	Takahashi et al.	428/458
*	I	US-2004/0219316	11-2004	Takahashi et al.	428/035.7
*	J	US-5,427,842	06-1995	Bland et al.	428/213
*	K	US-6,040,061	03-2000	Bland et al.	428/480
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2001-179916	07-2001	JP	Murooka	
	O	JP 2001-055454	02-2001	JP	Matsui et al	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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